Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination
10549801	FUNAHASHI, MASAKAZU

1794

Examiner Art Unit

SEARCHED				
Class	Subclass	Date	Examiner	
428	690, 917 (see EAST search printout for all listed - limited by keywords)	7-27-08	DG	
313	504, 506	7-27-08	DG	
257	E51.05, E51.051	7-27-08	DG	
564	426, 434	7-27-08	DG	

Dawn Garrett

SEARCH NOTES				
Search Notes	Date	Examiner		
EIC 1700 STIC structure search - see printout	7-22-08	DG		
Inventor Name Search	7-27-08	DG		
EAST search (see printout); Databases: JPO, EPO, DERWENT, USPAT, USPGPUB	7-27-08	DG		
updated EAST search (see printout); Databases: JPO, EPO, DERWENT, USPAT, USPGPUB	4-2-2009 and 4- 4-2009	DG		

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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